


<b>Search Notes</b>  	<b>Application/Control No.</b>  10675479	<b>Applicant(s)/Patent Under Reexamination</b>  PANDEY ET AL.
	<b>Examiner</b>  Wai, Eric C	<b>Art Unit</b>  2195

SEARCHED			
Class	Subclass	Date	Examiner
718	105	05/15/2007	ECW
709	203	05/15/2007	ECW

SEARCH NOTES		
Search Notes	Date	Examiner
East Search	05/15/2007	ECW
Inventor's Name Search	05/15/2007	ECW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner